

April 1991 Revised August 1999

## 74FR9245

# 9-Bit Bidirectional Transceiver with 3-STATE Outputs

#### **General Description**

The 74FR9245 contains nine non-inverting bidirectional buffers with 3-STATE outputs and is intended for bus-oriented applications. Current sinking capability is 64 mA on both the A and B Ports. The Transmit/Receive  $(T/\overline{R})$  input determines the direction of data flow through the bidirectional transceiver. Transmit (active-HIGH) enables data from A Ports to B Ports; Receive (active-LOW) enables data from B Ports to A Ports. The Output Enable input, when HIGH, disables both A and B Ports by placing them in a High Z condition.

#### **Features**

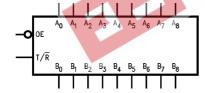
- Non-inverting buffers
- Bidirectional data path
- A and B output sink capability of 64 mA, source capability of 15 mA
- Guaranteed pin-to-pin skew, multiple output switching and 250 pf delay

# Ordering Code:

		40 4
Order Number	Package Number	Package Description
74FR9245SC	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74FR9245MSA	MSA24	24-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
74FR9245SPC	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-100, 0,300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code

## **Logic Symbol**



## **Connection Diagram**



# **Pin Descriptions**

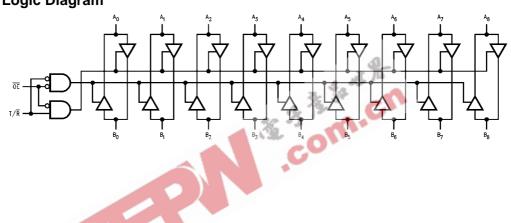
Pin Names	Description			
ŌE	Output Enable Input (Active-LOW)			
T/R	Transmit/Receive Input			
A <sub>0</sub> -A <sub>8</sub>	Side A Inputs or 3-STATE Outputs			
B <sub>0</sub> -B <sub>8</sub>	Side B Inputs or 3-STATE Outputs			

## **Truth Table**

Inputs		Output			
OE	T/R				
L	L	Bus B Data to Bus A			
L	Н	Bus A Data to Bus B			
Н	X	High Z State			

H = HIGH Voltage Level L = LOW Voltage Level X = Immaterial

# **Logic Diagram**



## **Absolute Maximum Ratings**(Note 1)

Storage Temperature  $-65^{\circ}\text{C} \text{ to } +150^{\circ}\text{C}$ 

 $\begin{array}{lll} \mbox{Ambient Temperature under Bias} & -55^{\circ}\mbox{C to } +125^{\circ}\mbox{C} \\ \mbox{Junction Temperature under Bias} & -55^{\circ}\mbox{C to } +150^{\circ}\mbox{C} \\ \mbox{V}_{\mbox{CC}} \mbox{ Pin Potential to Ground Pin} & -0.5\mbox{V to } +7.0\mbox{V} \end{array}$ 

Input Voltage (Note 2) -0.5 V to +7.0 VInput Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with  $V_{CC} = 0V$ )

Standard Output -0.5V to  $V_{CC}$ 3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated  $I_{OL}$  (mA) ESD Last Passing Voltage (Min) 4000V

# Recommended Operating Conditions

Free Air Ambient Temperature  $0^{\circ}\text{C to } +70^{\circ}\text{C}$  Supply Voltage +4.5V to +5.5V

**Note 1:** Absolute maximum ratings are value beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

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Note 2: Either voltage limit or current limit is sufficient to protect inputs.

#### **DC Electrical Characteristics**

Symbol	Parameter	Min	Тур	Max	Units	Vcc	Conditions
V <sub>IH</sub>	Input HIGH Voltage	2.0			V	30	Recognized HIGH Signal
V <sub>IL</sub>	Input LOW Voltage			0.8	2 V 3		Recognized LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltage			-1.2	V	Min	I <sub>IN</sub> = -18 mA
V <sub>OH</sub>	Output HIGH Voltage	2.4		13L	V	Min	$I_{OH} = -3 \text{ mA } (A_n, B_n)$
		2.0			V	Min	$I_{OH} = -15 \text{ mA } (A_n, B_n)$
V <sub>OL</sub>	Output LOW Voltage			0.55	V	Min	$I_{OL} = 64 \text{ mA } (A_n, B_n)$
I <sub>IH</sub>	Input HIGH Current			5	μА	Max	$V_{IN} = 2.7V (\overline{OE}, T/\overline{R})$
I <sub>BVI</sub>	Input HIGH Current Breakdown Test			7	μА	Max	$V_{IN} = 7.0V (\overline{OE}, T/\overline{R})$
I <sub>BVIT</sub>	Input HIGH Current Breakdown Test (I/O)			100	μА	Max	V <sub>IN</sub> = 5.5V (A <sub>n</sub> , B <sub>n</sub> )
$I_{IL}$	Input LOW Current			-250	μΑ	Max	$V_{IN} = 0.5V (\overline{OE}, T/\overline{R})$
V <sub>ID</sub>	Input Leakage Test	4.75			V	0.0	$I_{ID} = 1.9 \mu A$
							All Other Pins Grounded
I <sub>OD</sub>	Output Circuit 3.75 uA		^	μΑ 0.0	V <sub>IOD</sub> = 150 mV		
	Leakage Current			3.73	μΛ	0.0	All Other Pins Grounded
I <sub>IH</sub> + I <sub>OZH</sub>	Output Leakage Current			25	μΑ	Max	$V_{OUT} = 2.7V (A_n, B_n)$
I <sub>IL</sub> + I <sub>OZL</sub>	Output Leakage Current			-150	μΑ	Max	$V_{OUT} = 0.5V (A_n, B_n)$
I <sub>OS</sub>	Output Short-Circuit Current	-100		-225	mA	Max	$V_{OUT} = 0.0V (A_n, B_n)$
I <sub>CEX</sub>	Output HIGH Leakage Current			50	μΑ	Max	$V_{OUT} = V_{CC} (A_n, B_n)$
I <sub>ZZ</sub>	Bus Drainage Test			100	μΑ	0.0	$V_{OUT} = 5.25V (A_n, B_n)$
I <sub>CCH</sub>	Power Supply Current		55	80	mA	Max	All Outputs HIGH
I <sub>CCL</sub>	Power Supply Current		75	115	mA	Max	All Outputs LOW
I <sub>CCZ</sub>	Power Supply Current		65	85	mA	Max	Outputs 3-STATE
C <sub>IN</sub>	Input Capacitance		8.0		pF	5.0	OE, T/R
			17.0		pF	5.0	A <sub>n</sub> , B <sub>n</sub>

# **AC Electrical Characteristics**

Symbol	Parameter		T <sub>A</sub> = +25°C			$T_A = 0^{\circ}C \text{ to } +70^{\circ}C$	
			$\textbf{V}_{\textbf{CC}} = +\textbf{5.0V}$		$V_{CC} = +50V$		Units
			C <sub>L</sub> = 50 pF			$C_L = 50 \text{ pF}$	
		Min	Тур	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay	1.0	2.6	3.9	1.0	3.9	ns
t <sub>PHL</sub>	$A_n$ to $B_n$ or $B_n$ to $A_n$	1.0	1.7	3.9	1.0	3.9	115
t <sub>PZH</sub>	Output Enable Time	2.7	5.0	6.5	2.7	6.5	
$t_{PZL}$		2.7	4.3	6.5	2.7	6.5	ns
t <sub>PHZ</sub>	Output Disable Time	1.7	3.7	6.0	1.7	6.0	200
t <sub>PLZ</sub>		1.7	3.6	6.0	1.7	6.0	ns

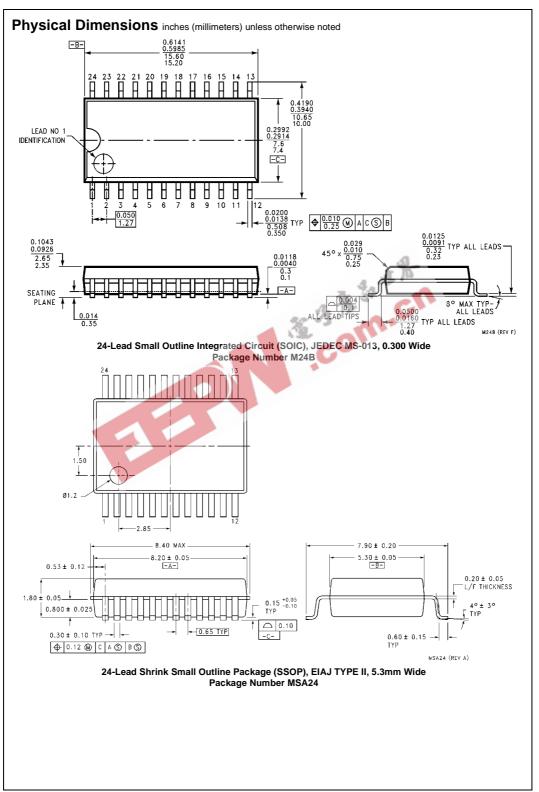
## **Extended AC Electrical Characteristics**

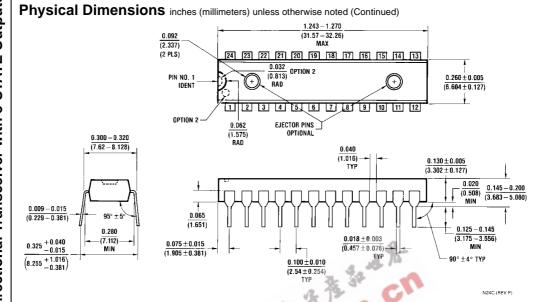
Symbol	Parameter	$T_{A} = 0^{\circ}C \text{ to } +70^{\circ}C$ $V_{CC} = +50V$ $C_{L} = 50 \text{ pF}$ Eight Outputs Switching (Note 3)		$T_A = 0^{\circ}C \text{ to } +70^{\circ}C$ $V_{CC} = +50V$ $C_L = 250 \text{ pF}$ (Note 4)		Units
		Min	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay	1.0	5.8	2.2	8.1	ns
t <sub>PHL</sub>	$A_n$ to $B_n$ or $B_n$ to $A_n$	1.0	5.8	2.2	8.1	115
t <sub>PZH</sub>	Output Enable Time	2.7	8.8			ns
$t_{PZL}$		2.7	8.8			115
t <sub>PHZ</sub>	Output Disable Time	1.7	7.0			ns
t <sub>PLZ</sub>		1.7	7.0			115
toshl	Pin-to-Pin Skew		2.0			
(Note 5)	for HL Transitions	2.0				ns
t <sub>OSLH</sub>	Pin-to-Pin Skew		1.0			no
(Note 5)	for LH Transitions		1.0			ns
t <sub>OST</sub>	Pin-to-Pin Skew for HI // H Transitions		3.0			ns
(Note 5)	for HL/LH Transitions		3.0			115

Note 3: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase, i.e., all LOW-to-HIGH, HIGH-to-LOW, 3-STATE-to-HIGH, etc.

Note 4: These specifications guaranteed but not tested. The limits represent propagation delays with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load. This specification pertains to single output switching only.

Note 5: Skew is defined as the absolute value of the difference between the actual propagation delays for any two outputs of the same device. The specification applies to any outputs switching HIGH-to-LOW (t<sub>OSHL</sub>), LOW-to-HIGH (t<sub>OSL</sub>), or HIGH-to-LOW and/or LOW-to-HIGH (t<sub>OST</sub>). Specifications guaranteed with all outputs switching in phase.





24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-100, 0.300 Wide Package Number N24C

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